

Features

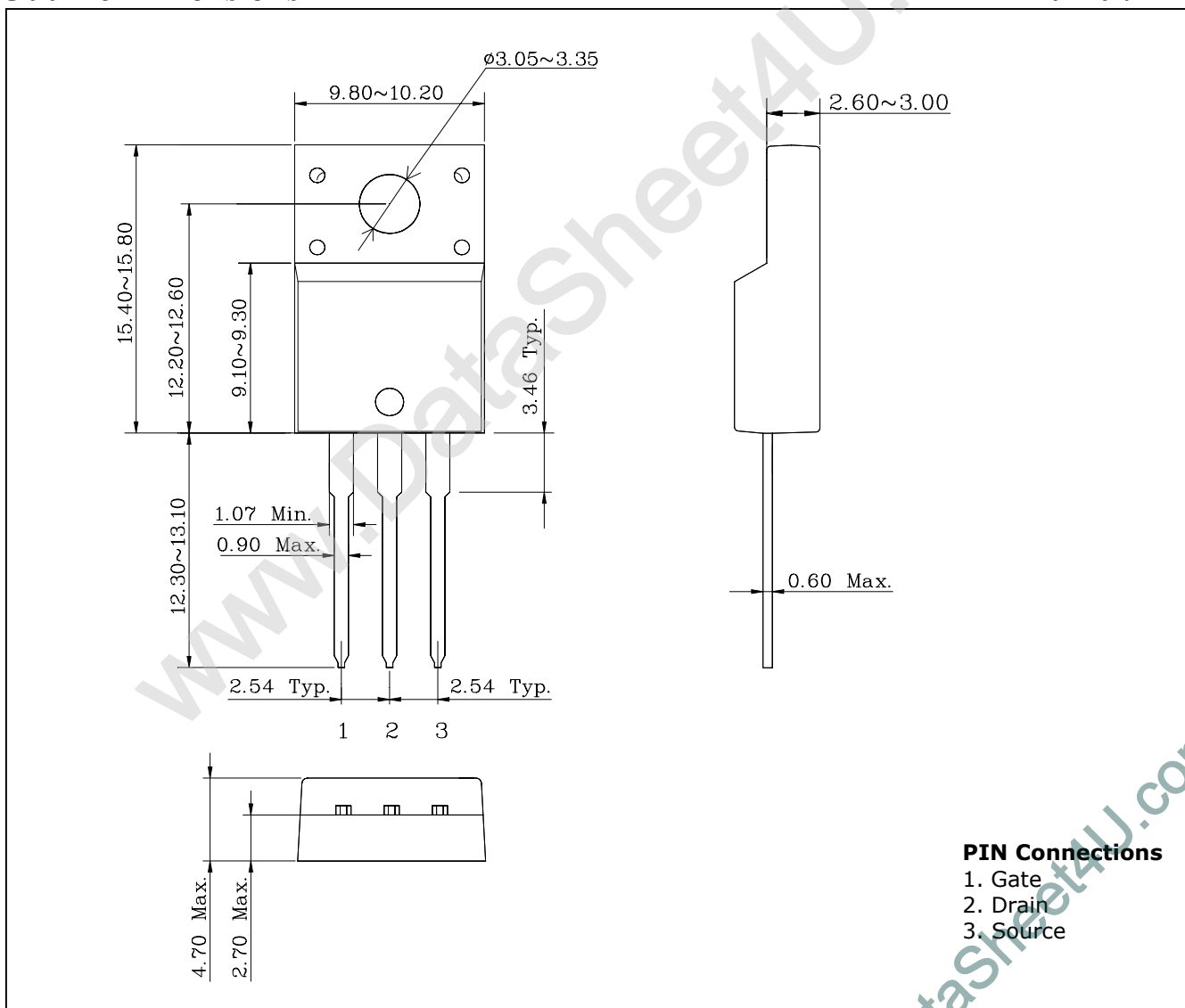
- Avalanche rugged technology.
- Low input capacitance.
- Low leakage current : 10 μA (Max.) @ $V_{\text{DS}}=200\text{V}$.
- Low $R_{\text{DS(on)}}$: 0.30 Ω (Typ.)

Ordering Information

| Type NO. | Marking | Package Code |
|----------|---------|--------------|
| STK630F | STK630 | TO-220F-3L |

Outline Dimensions

unit : mm



Absolute maximum ratings

| Characteristic | Symbol | Rating | | Unit |
|--|-----------|-------------------------|-----|------------------|
| Drain-source voltage | V_{DSS} | 200 | | V |
| Gate-source voltage | V_{GSS} | ± 30 | | V |
| Drain current (DC) * | I_D | $T_C=25^\circ\text{C}$ | 9 | A |
| | | $T_C=100^\circ\text{C}$ | 5.7 | A |
| Drain current (Pulsed) * | I_{DP} | 36 | | A |
| Drain power dissipation ($T_C=25^\circ\text{C}$) | P_D | 30 | | W |
| Single pulsed avalanche energy ② | E_{AS} | 162 | | mJ |
| Avalanche current (Repetitive) ① | I_{AR} | 9 | | A |
| Repetitive avalanche energy ① | E_{AR} | 7.2 | | mJ |
| Peak diode recovery dv/dt ③ | dv/dt | 5.0 | | V/ns |
| Junction temperature | T_J | 150 | | $^\circ\text{C}$ |
| Storage temperature range | T_{stg} | -55~150 | | $^\circ\text{C}$ |

* Limited by maximum junction temperature

Thermal Resistance

| Characteristic | Symbol | Typ. | Max. | Units |
|-------------------------------------|---------------|------|------|---------------------------|
| Thermal resistance junction-case | $R_{th(J-C)}$ | - | 4.16 | $^\circ\text{C}/\text{W}$ |
| Thermal resistance junction-ambient | $R_{th(J-A)}$ | - | 62.5 | |

Electrical Characteristics

(Tc=25°C)

| Characteristic | Symbol | Test Condition | Min. | Typ. | Max. | Unit |
|-----------------------------------|---------------|---|------|------|-----------|----------|
| Drain-source breakdown voltage | $V_{(BR)DSS}$ | $I_D=250\ \mu A, V_{GS}=0V$ | 200 | - | - | V |
| Gate threshold voltage | $V_{GS(th)}$ | $I_D=250\ \mu A, V_{DS}=V_{GS}$ | 2.0 | - | 4.0 | V |
| Drain-source cut-off current | I_{DSS} | $V_{DS}=200V, V_{GS}=0V$ | - | - | 10 | μA |
| Gate leakage current | I_{GSS} | $V_{DS}=0V, V_{GS}=\pm 30V$ | - | - | ± 100 | nA |
| Static drain-source on-resistance | $R_{DS(on)}$ | $V_{GS}=10V, I_D=4.5A$ ④ | - | - | 0.4 | Ω |
| Forward transfer conductance | g_{fs} | $V_{DS}=40V, I_D=4.5A$ ④ | - | 3.87 | - | S |
| Input capacitance | C_{iss} | $V_{GS}=0V, V_{DS}=25V$ $f=1\ MHz$ | - | 550 | - | pF |
| Output capacitance | C_{oss} | | - | 110 | - | |
| Reverse transfer capacitance | C_{rss} | | - | 40 | - | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD}=100V, I_D=9A$ $R_G=12\ \Omega$ Fig 13. ④ ⑤ | - | 13 | - | ns |
| Rise time | t_r | | - | 13 | - | |
| Turn-off delay time | $t_{d(off)}$ | | - | 30 | - | |
| Fall time | t_f | | - | 18 | - | |
| Total gate charge | Q_g | $V_{DS}=160V, V_{GS}=10V,$ $I_D=9A$ Fig 12. ④ ⑤ | - | 22 | - | nC |
| Gate-source charge | Q_{gs} | | - | 4.3 | - | |
| Gate-drain charge | Q_{gd} | | - | 10.9 | - | |

Source-Drain Diode Ratings and Characteristics

(Tc=25°C)

| Characteristic | Symbol | Test Condition | Min | Typ | Max | Units |
|---------------------------|----------|---|-----|------|-----|---------|
| Source current (DC) | I_S | Integral reverse diode in the MOSFET | - | - | 9 | A |
| Source current (Pulsed) ① | I_{SP} | | - | - | 36 | |
| Diode forward voltage ④ | V_{SD} | $V_{GS}=0V, I_S=9A$ | - | - | 1.5 | V |
| Reverse recovery time | t_{rr} | $I_F=9A$ | - | 140 | - | ns |
| Reverse recovery charge | Q_{rr} | $dI_S/dt=100A/\mu S$ ④ | - | 0.87 | - | μC |

Note ;

- ① Repetitive rating : Pulse width limited by maximum junction temperature
- ② $L=3mH, I_{AS}=9A, V_{DD}=50V, R_G=27\ \Omega$, starting $T_J=25\ ^\circ C$
- ③ $I_{SD} \leq 9A, di/dt \leq 220A/\mu S, V_{DD}=100V$, starting $T_J=25\ ^\circ C$
- ④ Pulse Test : Pulse Width $\leq 400\ \mu S$, Duty cycle $\leq 2\%$
- ⑤ Essentially independent of operating temperature

Electrical Characteristic Curves

Fig. 1 $I_D - V_{DS}$

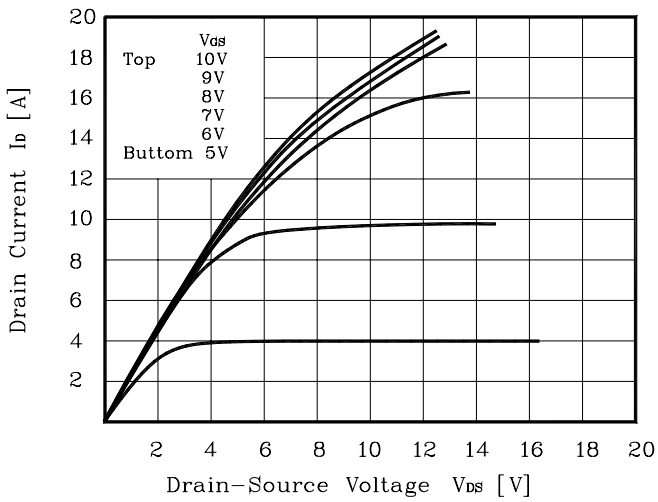


Fig. 2 $I_D - V_{GS}$

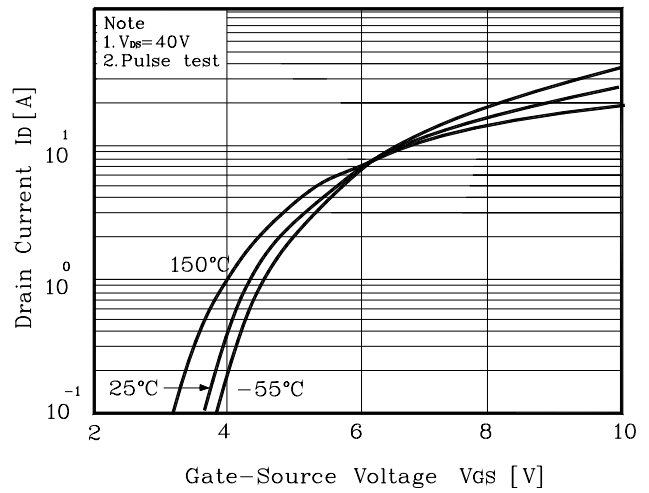


Fig. 3 $R_{DS(on)} - I_D$

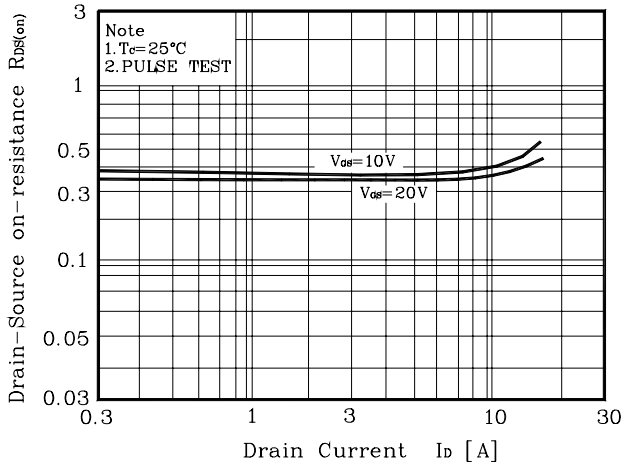


Fig. 4 $I_S - V_{SD}$

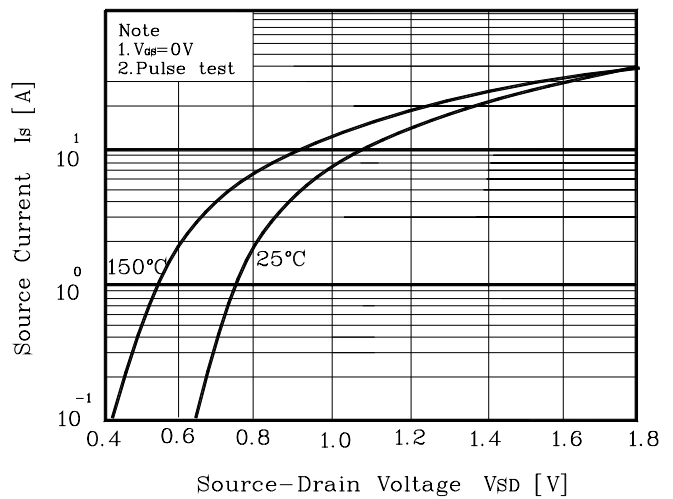


Fig. 5 $V_{GS} - Q_G$

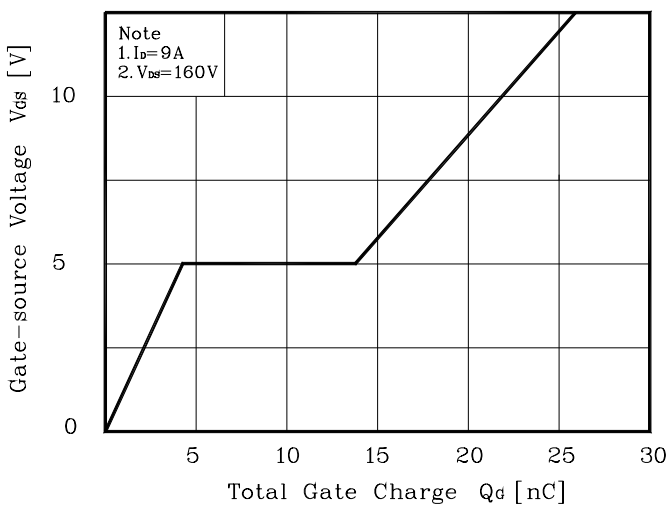


Fig. 6 Capacitance - V_{DS}

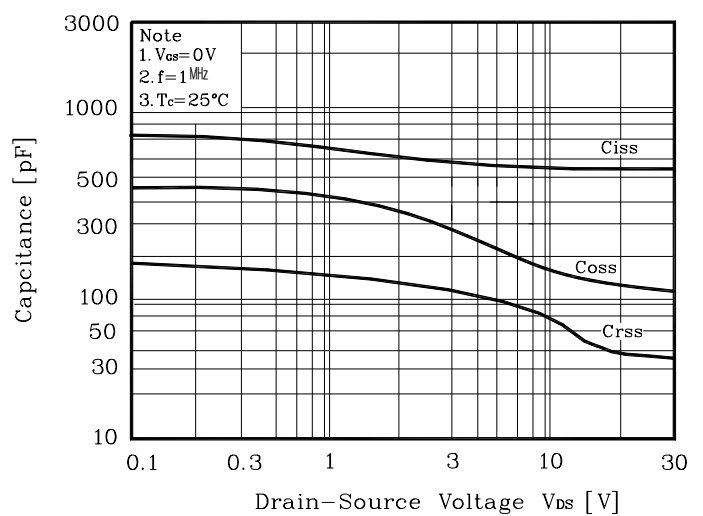


Fig. 7 $V_{(BR)DSS} - T_J$

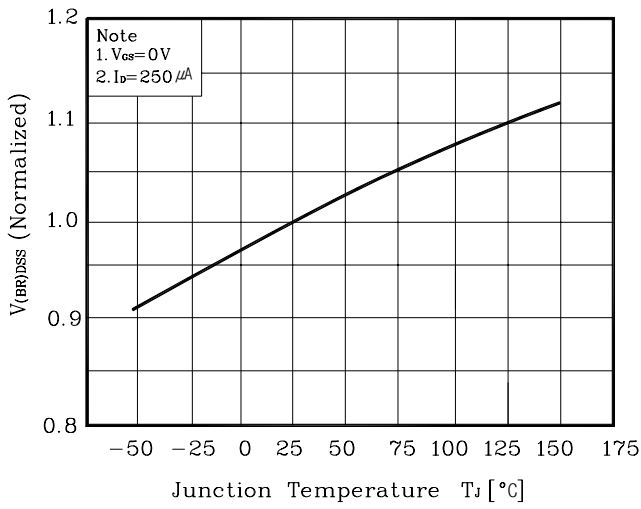


Fig. 8 $R_{DS(on)} - T_J$

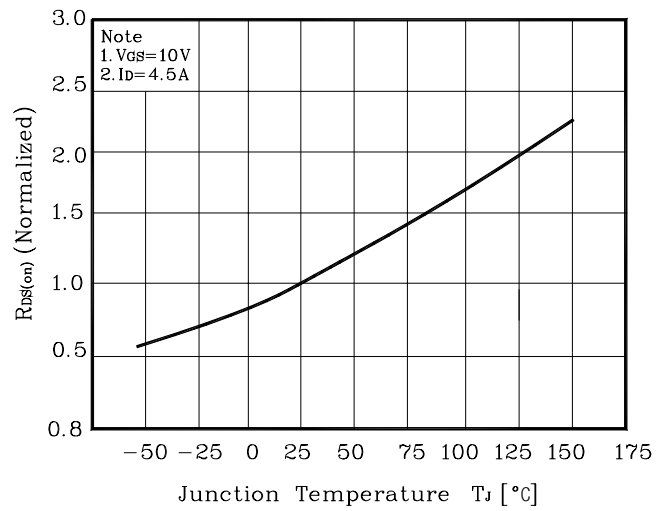


Fig. 9 $I_D - T_C$

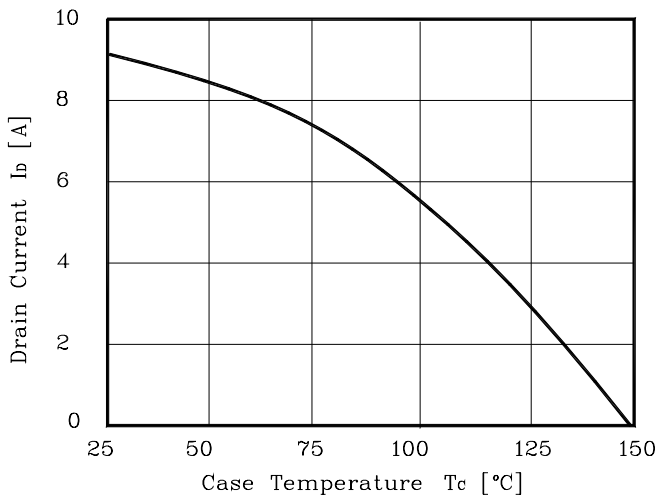


Fig. 10 Safe operating Area

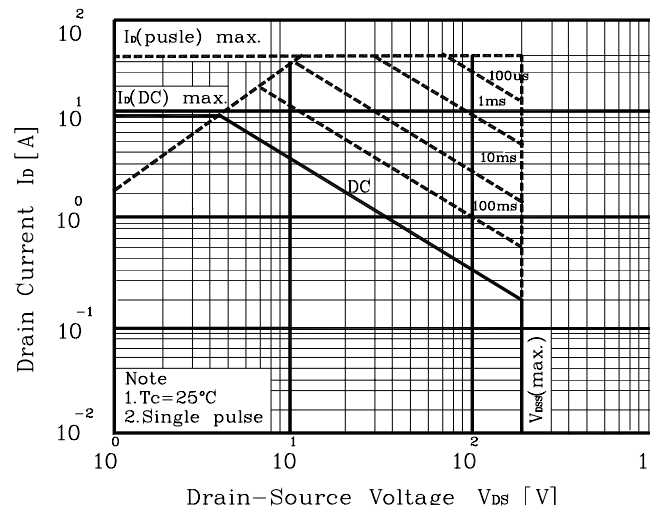


Fig. 11 Thermal Response

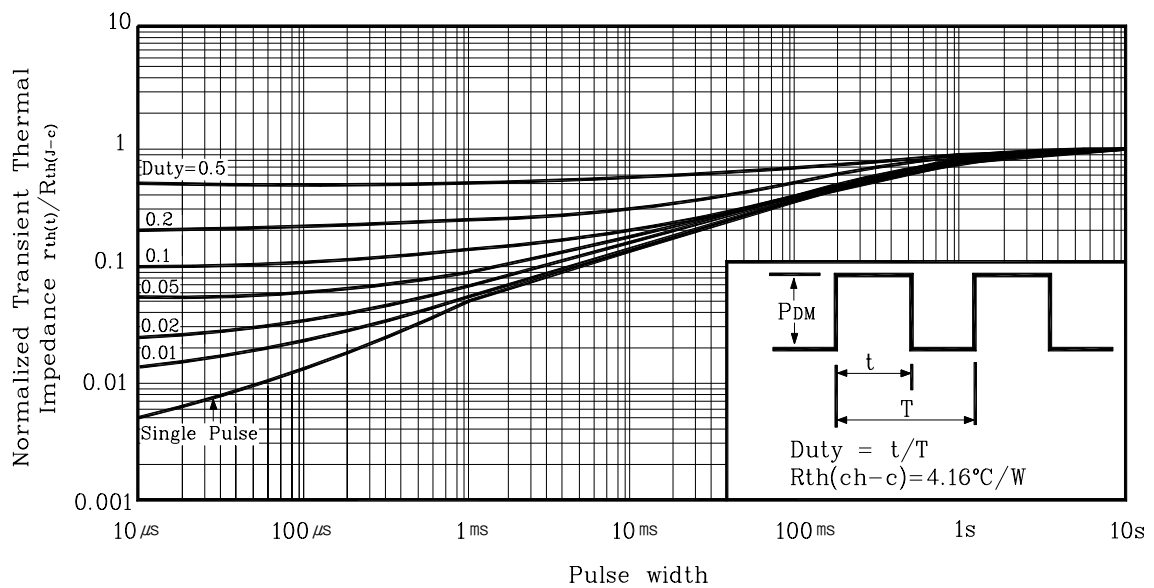


Fig. 12 Gate Charge Test Circuit & Waveform

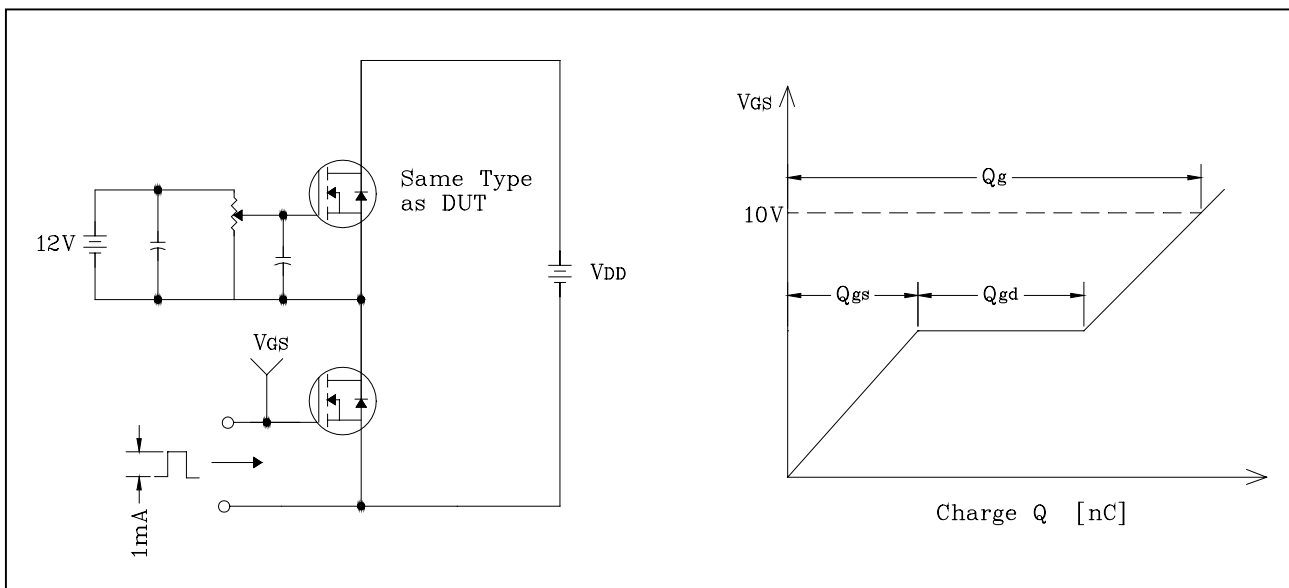


Fig. 13 Switching Time Test Circuit & Waveform

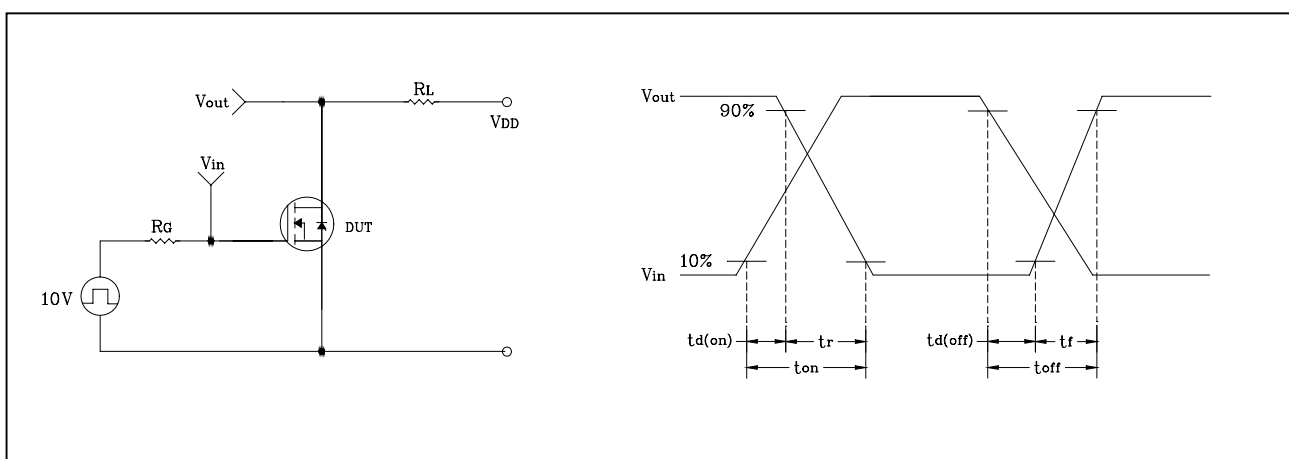


Fig. 14 E_{AS} Test Circuit & Waveform

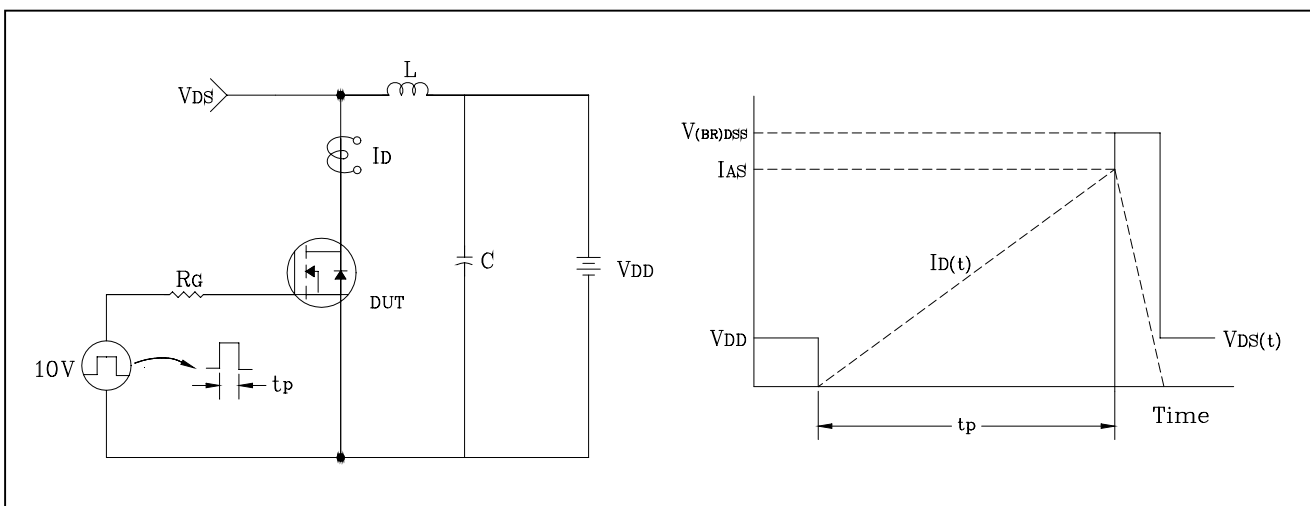
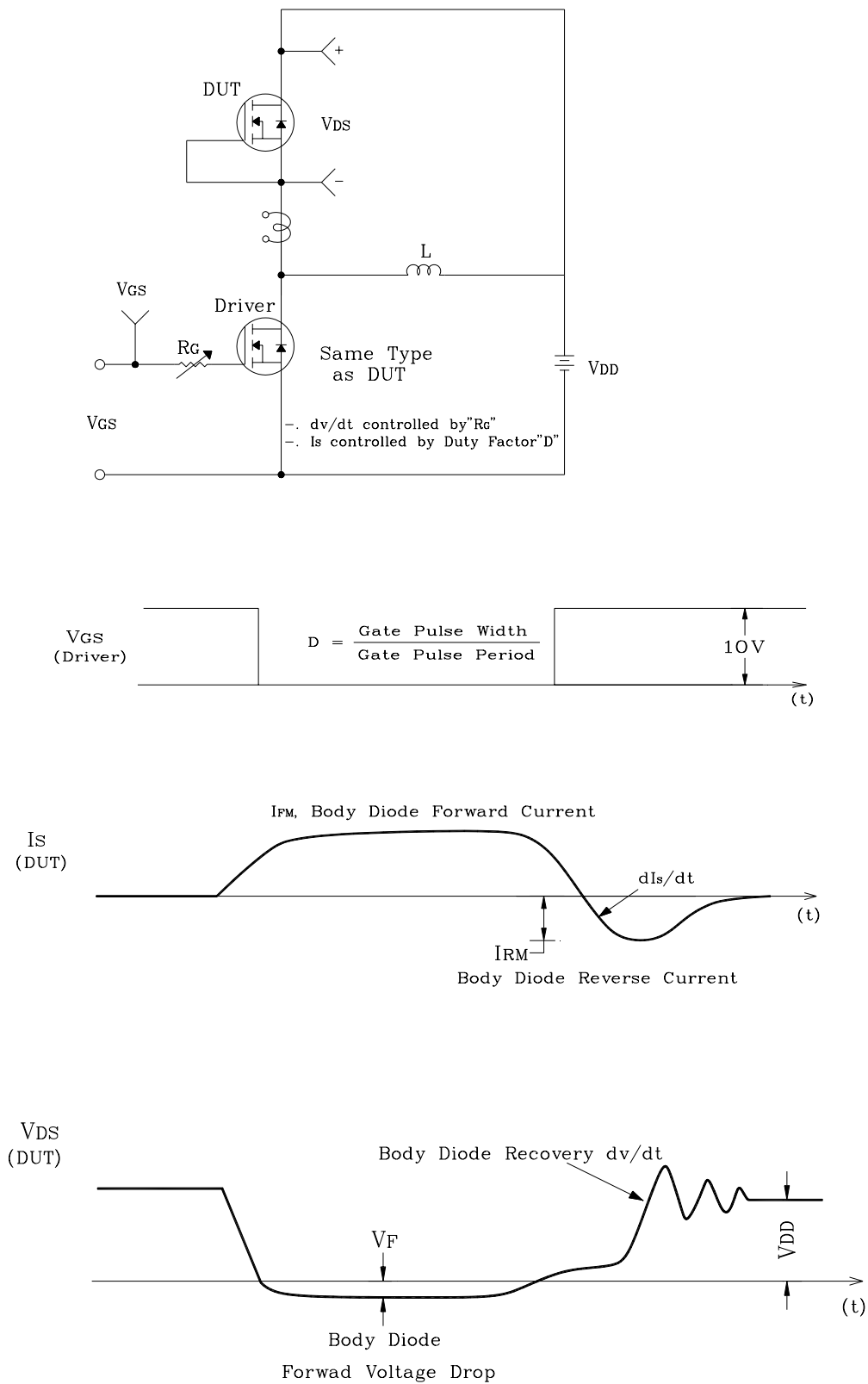


Fig. 15 Peak Diode Recovery dv/dt Test Circuit & Waveform



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